

#### 4-OUTPUT VERY LOW POWER PCIE GEN 1-2-3-4 CLOCK GENERATOR

9FGV0441

# **Description**

The 9FGV0441 is an 4-output very low power clock generator for PCIe Gen 1, 2, 3 and 4 applications with integrated output terminations providing Zo =  $100\Omega$ . The device has 4 output enables for clock management and supports 2 different spread spectrum levels in addition to spread off.

## **Recommended Application**

PCIe Gen1-4 clock generation for Riser Cards, Storage, Networking, JBOD, Communications, Access Points

## **Output Features**

- 4 0.7V low-power HCSL-compatible (LP-HCSL) DIF pairs w/Zo=100 $\Omega$
- 1 1.8V LVCMOS REF output w/ Wake-On-Lan (WOL) support

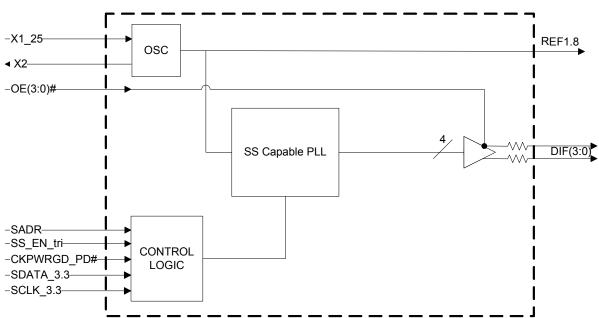
# **Key Specifications**

- DIF cycle-to-cycle jitter <50ps
- DIF output-to-output skew <50ps</li>
- DIF phase jitter is PCIe Gen1-2-3-4 compliant
- REF phase jitter is < 1.5ps RMS

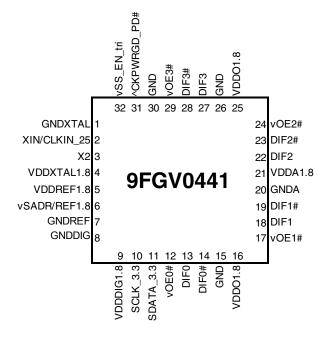
#### Features/Benefits

- Integrated terminations provide 100Ω differential Zo; reduced component count and board space
- 1.8V operation; reduced power consumption
- OE# pins; support DIF power management
- LP-HCSL differential clock outputs; reduced power and board space
- Programmable Slew rate for each output; allows tuning for various line lengths
- Programmable output amplitude; allows tuning for various application environments
- DIF outputs blocked until PLL is locked; clean system start-up
- Selectable 0%, -0.25% or -0.5% spread on DIF outputs; reduces EMI
- External 25MHz crystal; supports tight ppm with 0 ppm synthesis error
- Configuration can be accomplished with strapping pins;
   SMBus interface not required for device control
- 3.3V tolerant SMBus interface works with legacy controllers
- Space saving 32-pin 5x5 mm VFQFPN; minimal board space
- Selectable SMBus addresses; multiple devices can easily share an SMBus segment

# **Block Diagram**



# **Pin Configuration**



#### 32-pin VFQFPN, 5x5 mm, 0.5mm pitch

^ prefix indicates internal 120KOhm pull up resistor v prefix indicates internal 120KOhm pull down resistor

#### **SMBus Address Selection Table**

	SADR	Address	+ Read/Write Bit
State of SADR on first application	0	1101000	Х
of CKPWRGD_PD#	1	1101010	x

#### **Power Management Table**

CKPWRGD PD#	SMBus		DIFx		REF
CKFWKGD_FD#	OE bit	oit OEx# True O/P Comp. O/P		INLI	
0	Х	Х	Low	Low	Hi-Z <sup>1</sup>
1	1	0	Running	Running	Running
1	0	1	Low	Low	Low

<sup>1.</sup> REF is Hi-Z until the 1st assertion of CKPWRGD\_PD# high. After this, when CKPWRG\_PD# is low, REF is Low.

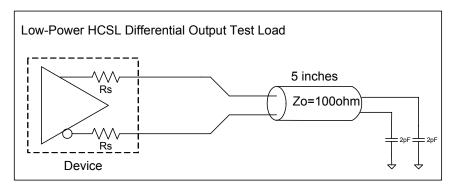
#### **Power Connections**

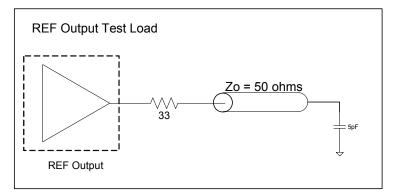
Pin Number		Description
VDD	GND	Description
4	1	XTAL Analog
5	7	REF Output
9	8, 30	Digital Power
16, 25	15, 26	DIF outputs
21	20	PLL Analog

# **Pin Descriptions**

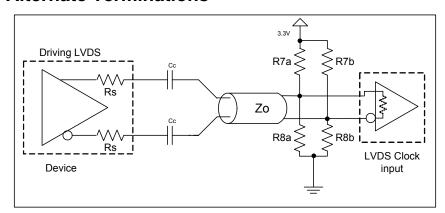
Pin#	Pin Name	Type	Pin Description
1	GNDXTAL	GND	GND for XTAL
2	XIN/CLKIN_25	IN	Crystal input or Reference Clock input. Nominally 25MHz.
3	X2	OUT	Crystal output.
4	VDDXTAL1.8	PWR	Power supply for XTAL, nominal 1.8V
5	VDDREF1.8	PWR	VDD for REF output. nominal 1.8V.
6	vSADR/REF1.8	LATCHED I/O	Latch to select SMBus Address/1.8V LVCMOS copy of X1 pin.
7	GNDREF	GND	Ground pin for the REF outputs.
8	GNDDIG	GND	Ground pin for digital circuitry
9	VDDDIG1.8	PWR	1.8V digital power (dirty power)
10	SCLK_3.3	IN	Clock pin of SMBus circuitry, 3.3V tolerant.
11	SDATA_3.3	I/O	Data pin for SMBus circuitry, 3.3V tolerant.
12	vOE0#	IN	Active low input for enabling DIF pair 0. This pin has an internal pull-down.  1 =disable outputs, 0 = enable outputs
13	DIF0	OUT	Differential true clock output
14	DIF0#	OUT	Differential Complementary clock output
15	GND	GND	Ground pin.
16	VDDO1.8	PWR	Power supply for outputs, nominally 1.8V.
17	vOE1#	IN	Active low input for enabling DIF pair 1. This pin has an internal pull-down.  1 =disable outputs, 0 = enable outputs
18	DIF1	OUT	Differential true clock output
19	DIF1#	OUT	Differential Complementary clock output
20	GNDA	GND	Ground pin for the PLL core.
21	VDDA1.8	PWR	1.8V power for the PLL core.
22	DIF2	OUT	Differential true clock output
23	DIF2#	OUT	Differential Complementary clock output
24	vOE2#	IN	Active low input for enabling DIF pair 2. This pin has an internal pull-down.  1 =disable outputs, 0 = enable outputs
25	VDDO1.8	PWR	Power supply for outputs, nominally 1.8V.
26	GND	GND	Ground pin.
27	DIF3	OUT	Differential true clock output
28	DIF3#	OUT	Differential Complementary clock output
29	vOE3#	IN	Active low input for enabling DIF pair 3. This pin has an internal pull-down.  1 =disable outputs, 0 = enable outputs
30	GND	GND	Ground pin.
31	^CKPWRGD_PD#	IN	Input notifies device to sample latched inputs and start up on first high assertion.  Low enters Power Down Mode, subsequent high assertions exit Power Down  Mode. This pin has internal pull-up resistor.
32	vSS_EN_tri	LATCHED IN	Latched select input to select spread spectrum amount at initial power up : $1 = -0.5\%$ spread, $M = -0.25\%$ , $0 = Spread Off$

# **Test Loads**





# **Alternate Terminations**



Driving LVDS inputs with the 9FGV0441

	,	Value	
	Receiver has Receiver does not		
Component	termination	have termination	Note
R7a, R7b	10K ohm	140 ohm	
R8a, R8b	5.6K ohm	75 ohm	
Cc	0.1 uF	0.1 uF	
Vcm	1.2 volts	1.2 volts	

# **Absolute Maximum Ratings**

Stresses above the ratings listed below can cause permanent damage to the 9FGV0441. These ratings, which are standard values for IDT commercially rated parts, are stress ratings only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods can affect product reliability. Electrical parameters are guaranteed only over the recommended operating temperature range.

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
1.8V Supply Voltage	VDDx1.8	Applies to All VDD pins	-0.5		2.5	V	1,2
Input Voltage	$V_{IN}$		-0.5		$V_{DD}+0.3V$	V	1, 3
Input High Voltage, SMBus	$V_{IHSMB}$	SMBus clock and data pins			3.6V	V	1
Storage Temperature	Ts		-65		150	°C	1
Junction Temperature	Tj				125	ç	1
Input ESD protection	ESD prot	Human Body Model	2000			V	1

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

# **Electrical Characteristics—Current Consumption**

TA = T<sub>COM</sub> or T<sub>IND</sub>: Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Operating Supply Current	I <sub>DDAOP</sub>	VDDA, All outputs active @100MHz		6	8	mA	1
	I <sub>DDOP</sub>	VDD, All outputs active @100MHz		26	30	mA	1
Suspend Supply Current	I <sub>DDSUSP</sub>	VDDxxx, PD# = 0, Wake-On-LAN enabled		6	8	mA	1
Powerdown Current	I <sub>DDPD</sub>	PD#=0		0.6	1	mA	1, 2

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

# Electrical Characteristics-Output Duty Cycle, Jitter, and Skew Characteristics

 $TA = T_{COM}$  or  $T_{IND}$ ; Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Duty Cycle	t <sub>DC</sub>	Measured differentially, PLL Mode	45	50	55	%	1
Skew, Output to Output	t <sub>sk3</sub>	V <sub>T</sub> = 50%		34	50	ps	1
Jitter, Cycle to cycle	t <sub>icyc-cyc</sub>	PLL mode		14	50	ps	1,2

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

<sup>&</sup>lt;sup>2</sup> Operation under these conditions is neither implied nor guaranteed.

<sup>&</sup>lt;sup>3</sup> Not to exceed 2.5V.

<sup>&</sup>lt;sup>2</sup>Assuming REF is not running in power down state

<sup>&</sup>lt;sup>2</sup> Measured from differential waveform

# **Electrical Characteristics-Input/Supply/Common Parameters-Normal Operating Conditions**

 $TA = T_{COM}$  or  $T_{IND}$ . Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

OOM - 114D, 1-1- 7	J -	I	1				
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
1.8V Supply Voltage	VDD <sub>x</sub> 1.8	Supply voltage for core, analog and single-ended LVCMOS outputs	1.7	1.8	1.9	٧	1
Ambient Operating Temperature	T <sub>IND</sub>	Industrial range	-40	25	85	°C	1
Input High Voltage	$V_{IH}$	Single-ended inputs, except SMBus	0.75 V <sub>DD</sub>		$V_{DD} + 0.3$	V	1
Input Mid Voltage	$V_{IM}$	Single-ended tri-level inputs ('_tri' suffix, if present)	$0.4~V_{DD}$		0.6 V <sub>DD</sub>	V	1
Input Low Voltage	$V_{IL}$	Single-ended inputs, except SMBus	-0.3		0.25 V <sub>DD</sub>	V	1
Schmitt Trigger Positive Going Threshold Voltage	V <sub>T+</sub>	Single-ended inputs, where indicated	0.4 V <sub>DD</sub>		0.7 V <sub>DD</sub>	V	1
Schmitt Trigger Negative Going Threshold Voltage	V <sub>T-</sub>	Single-ended inputs, where indicated	0.1 V <sub>DD</sub>		0.4 V <sub>DD</sub>	٧	1
Hysteresis Voltage	$V_{H}$	V <sub>T+</sub> - V <sub>T-</sub>	0.1 V <sub>DD</sub>		0.4 V <sub>DD</sub>	٧	1
Output High Voltage	$V_{IH}$	Single-ended outputs, except SMBus. I <sub>OH</sub> = -2mA	V <sub>DD</sub> -0.45			٧	1
Output Low Voltage	$V_{IL}$	Single-ended outputs, except SMBus. I <sub>OL</sub> = -2mA			0.45	V	1
	I <sub>IN</sub>	Single-ended inputs, $V_{IN} = GND$ , $V_{IN} = VDD$	-5		5	uA	1
Inner de Commonde		Single-ended inputs					
Input Current	I <sub>INP</sub>	$V_{IN} = 0 \text{ V}$ ; Inputs with internal pull-up resistors	-200		200	uA	1
		$V_{IN} = VDD$ ; Inputs with internal pull-down resistors					
Input Frequency	F <sub>in</sub>	XTAL, or X1 input	23	25	27	MHz	1
Pin Inductance	$L_{pin}$				7	nΗ	1
Consoitance	C <sub>IN</sub>	Logic Inputs, except DIF_IN	1.5		5	pF	1
Capacitance	C <sub>OUT</sub>	Output pin capacitance			6	pF	1
Clk Stabilization	T <sub>STAB</sub>	From V <sub>DD</sub> Power-Up and after input clock stabilization or de-assertion of PD# to 1st clock		0.6	1.8	ms	1,2
SS Modulation Frequency	f <sub>MOD</sub>	Allowable Frequency (Triangular Modulation)	31	31.6	32	kHz	1
OE# Latency	t <sub>LATOE#</sub>	DIF start after OE# assertion DIF stop after OE# deassertion	2	3	4	clocks	1,3
Tdrive_PD#	t <sub>DRVPD</sub>	DIF output enable after PD# de-assertion		4	300	us	1,3
Tfall	t <sub>F</sub>	Fall time of single-ended control inputs			5	ns	1,2
Trise	t <sub>R</sub>	Rise time of single-ended control inputs			5	ns	1,2
SMBus Input Low Voltage	V <sub>ILSMB</sub>	$V_{DDSMB} = 3.3V$ , see note 4 for $V_{DDSMB} < 3.3V$			0.8	V	1,4
SMBus Input High Voltage	V <sub>IHSMB</sub>	$V_{DDSMB} = 3.3V$ , see note 5 for $V_{DDSMB} < 3.3V$	2.1		3.6	V	1,5
SMBus Output Low Voltage	V <sub>OLSMB</sub>	@ I <sub>PULLUP</sub>			0.4	V	1
SMBus Sink Current	I <sub>PULLUP</sub>	@ V <sub>OL</sub>	4			mA	1
Nominal Bus Voltage	V <sub>DDSMB</sub>		1.7		3.6	V	1
SCLK/SDATA Rise Time	t <sub>RSMB</sub>	(Max VIL - 0.15) to (Min VIH + 0.15)			1000	ns	1
SCLK/SDATA Fall Time	t <sub>FSMB</sub>	(Min VIH + 0.15) to (Max VIL - 0.15)			300	ns	1
SMBus Operating Frequency	f <sub>MAXSMB</sub>	Maximum SMBus operating frequency			400	kHz	1

<sup>&</sup>lt;sup>1</sup> Guaranteed by design and characterization, not 100% tested in production.

<sup>&</sup>lt;sup>2</sup> Control input must be monotonic from 20% to 80% of input swing.

<sup>&</sup>lt;sup>3</sup> Time from deassertion until outputs are >200 mV

 $<sup>^4</sup>$  For  $V_{\text{DDSMB}} < 3.3 V, \ V_{\text{ILSMB}} <= 0.35 V_{\text{DDSMB}}$ 

 $<sup>^{5}</sup>$  For  $V_{DDSMB}$  < 3.3V,  $V_{IHSMB}$  >= 0.65 $V_{DDSMB}$ 

# Electrical Characteristics-DIF 0.7V Low Power HCSL Outputs

TA = T<sub>COM</sub> or T<sub>IND</sub>: Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Slew rate	Trf	Scope averaging on 3.0V/ns setting	2	3.1	4.3	V/ns	1, 2, 3
Siew rate	111	Scope averaging on 2.0V/ns setting	1.5	2.3	3.5	V/ns	1, 2, 3
Slew rate matching	ΔTrf	Slew rate matching, Scope averaging on		3	20	%	1,2,4
Voltage High	V <sub>HIGH</sub>	Statistical measurement on single-ended signal using oscilloscope math function. (Scope	660	794	850	mV	1,7
Voltage Low	$V_{LOW}$	averaging on)	-150	21	150	1117	1
Max Voltage	Vmax	Measurement on single ended signal using		816	1150	mV	1
Min Voltage	Vmin	absolute value. (Scope averaging off)	-300	-15		IIIV	1
Vswing	Vswing	Scope averaging off	300	1551		mV	1,2
Crossing Voltage (abs)	Vcross_abs	Scope averaging off	300	397	550	mV	1,5
Crossing Voltage (var)	∆-Vcross	Scope averaging off		15	140	mV	1,6

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

# Electrical Characteristics—Filtered Phase Jitter Parameters - PCle Common Clocked (CC) Architectures

T<sub>AMB</sub> = over the specified operating range. Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	Specification Limit	UNITS	NOTES
t <sub>jphPCleG1-CC</sub>		PCIe Gen 1	21	25	35	86	ps (p-p)	1, 2, 3
	Phase Jitter, PLL Mode	PCIe Gen 2 Low Band 10kHz < f < 1.5MHz (PLL BW of 5-16MHz, 8-16MHz, CDR = 5MHz)	0.9	0.9	1.1	3	ps (rms)	1, 2
TjphPCIeG2-CC		PCIe Gen 2 High Band 1.5MHz < f < Nyquist (50MHz) (PLL BW of 5-16MHz, 8-16MHz, CDR = 5MHz)	1.5	1.6	1.9	3.1	ps (rms)	1, 2
t <sub>jphPCleG3-CC</sub>		PCIe Gen 3 (PLL BW of 2-4MHz, 2-5MHz, CDR = 10MHz)	0.3	0.37	0.44	1	ps (rms)	1, 2
t <sub>jphPCleG4-CC</sub>		PCIe Gen 4 (PLL BW of 2-4MHz, 2-5MHz, CDR = 10MHz)	0.3	0.37	0.44	0.5	ps (rms)	1, 2

#### Notes on PCle Filtered Phase Jitter Table

<sup>&</sup>lt;sup>2</sup> Measured from differential waveform

<sup>&</sup>lt;sup>3</sup> Slew rate is measured through the Vswing voltage range centered around differential 0V. This results in a +/-150mV window around differential 0V.

<sup>&</sup>lt;sup>4</sup> Matching applies to rising edge rate for Clock and falling edge rate for Clock#. It is measured using a +/-75mV window centered on the average cross point where Clock rising meets Clock# falling. The median cross point is used to calculate the voltage thresholds the oscilloscope is to use for the edge rate calculations.

<sup>&</sup>lt;sup>5</sup> Vcross is defined as voltage where Clock = Clock# measured on a component test board and only applies to the differential rising edge (i.e. Clock rising and Clock# falling).

<sup>&</sup>lt;sup>6</sup> The total variation of all Vcross measurements in any particular system. Note that this is a subset of Vcross\_min/max (Vcross absolute) allowed. The intent is to limit Vcross induced modulation by setting Δ-Vcross to be smaller than Vcross absolute.

At default SMBus settings.

<sup>&</sup>lt;sup>1</sup> Applies to all differential outputs, guaranteed by design and characterization.

<sup>&</sup>lt;sup>2</sup> Calculated from Intel-supplied Clock Jitter Tool, with spread on and off.

<sup>&</sup>lt;sup>3</sup> Sample size of at least 100K cycles. This figure extrapolates to 108ps pk-pk at 1M cycles for a BER of 1<sup>-12</sup>.

#### **Electrical Characteristics-REF**

 $TA = T_{COM}$  or  $T_{IND}$ ; Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	Notes
Long Accuracy	ppm	see Tperiod min-max values		0	1 111/1/	ppm	1,2
Clock period	T <sub>period</sub>	25 MHz output nominal		40		ns	1,2
Rise/Fall Slew Rate	t <sub>rf1</sub>	Byte 3 = 1F, $V_{OH} = VDD-0.45V$ , $V_{OL} = 0.45V$	0.6	1	1.8	V/ns	1,3
Rise/Fall Slew Rate	t <sub>rf1</sub>	Byte 3 = 5F, $V_{OH} = VDD-0.45V$ , $V_{OL} = 0.45V$	1.0	1.6	2.5	V/ns	1,3
Rise/Fall Slew Rate	t <sub>rf1</sub>	Byte 3 = 9F, $V_{OH} = VDD-0.45V$ , $V_{OL} = 0.45V$	1.3	2	3.0	V/ns	1,3
Rise/Fall Slew Rate	t <sub>rf1</sub>	Byte 3 = DF, $V_{OH} = VDD-0.45V$ , $V_{OL} = 0.45V$	1.4	2.1	3.1	V/ns	1,3
Duty Cycle	d <sub>t1</sub>	$V_T = VDD/2 V$	45	53.2	55	%	1,4
Duty Cycle Distortion	d <sub>tcd</sub>	$V_T = VDD/2 V$	0	2	4	%	1,5
Jitter, cycle to cycle	t <sub>jcyc-cyc</sub>	$V_T = VDD/2 V$		0	75	ps	1,4
Noise floor	t <sub>jdBc1k</sub>	1kHz offset		-130	-105	dBc	1,4
Noise floor	t <sub>jdBc10k</sub>	10kHz offset to Nyquist		-140	-120	dBc	1,4
Jitter, phase	t <sub>jphREF</sub>	12kHz to 5MHz		0.68	1.5	ps (rms)	1,4

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

# Clock Periods-Differential Outputs with Spread Spectrum Disabled

			Measurement Window							
	Center	1 Clock	1us	0.1s	0.1s	0.1s	1us	1 Clock		
SSC OFF	Freq. MHz	-c2c jitter AbsPer Min	-SSC Short-Term Average Min	- ppm Long-Term Average Min	0 ppm Period Nominal	+ ppm Long-Term Average Max	+SSC Short-Term Average Max	+c2c jitter AbsPer Max	Units	Notes
DIF	100.00	9.94900		9.99900	10.00000	10.00100		10.05100	ns	1,2

# Clock Periods-Differential Outputs with -0.5% Spread Spectrum Enabled

		Measurement Window								
	Center	1 Clock	1us	0.1s	0.1s	0.1s	1us	1 Clock		
SSC ON	Freq. MHz	-c2c jitter AbsPer Min	-SSC Short-Term Average Min	- ppm Long-Term Average Min	0 ppm Period Nominal	+ ppm Long-Term Average Max	+SSC Short-Term Average Max	+c2c jitter AbsPer Max	Units	Notes
DIF	99.75	9.94906	9.99906	10.02406	10.02506	10.02607	10.05107	10.10107	ns	1,2

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

<sup>&</sup>lt;sup>2</sup> All Long Term Accuracy and Clock Period specifications are guaranteed assuming that REF is trimmed to 25.00 MHz

<sup>&</sup>lt;sup>3</sup> Typical value occurs when REF slew rate is set to default value

<sup>&</sup>lt;sup>4</sup> When driven by a crystal.

<sup>&</sup>lt;sup>5</sup> When driven by an external oscillator via the X1 pin. X2 should be floating in this case.

<sup>&</sup>lt;sup>2</sup> All Long Term Accuracy and Clock Period specifications are guaranteed assuming that REF is trimmed to 25.00 MHz

#### **General SMBus Serial Interface Information**

#### **How to Write**

- · Controller (host) sends a start bit
- · Controller (host) sends the write address
- IDT clock will acknowledge
- Controller (host) sends the beginning byte location = N
- IDT clock will acknowledge
- Controller (host) sends the byte count = X
- IDT clock will acknowledge
- Controller (host) starts sending Byte N through Byte N+X-1
- IDT clock will acknowledge each byte one at a time
- Controller (host) sends a Stop bit

	Index Block Write Operation							
Controll	er (Host)		IDT (Slave/Receiver)					
Т	starT bit							
Slave A	Address							
WR	WRite							
			ACK					
Beginning	g Byte = N							
			ACK					
Data Byte	Count = X							
			ACK					
Beginnin	g Byte N							
			ACK					
0		×						
0		X Byte	0					
0		Ð	0					
			0					
Byte N	+ X - 1							
			ACK					
Р	stoP bit							

Note: Read/Write address is latched on SADR pin.

#### **How to Read**

- · Controller (host) will send a start bit
- Controller (host) sends the write address
- IDT clock will acknowledge
- Controller (host) sends the beginning byte location = N
- IDT clock will acknowledge
- · Controller (host) will send a separate start bit
- Controller (host) sends the read address
- IDT clock will acknowledge
- IDT clock will send the data byte count = X
- IDT clock sends Byte N+X-1
- IDT clock sends Byte 0 through Byte X (if X<sub>(H)</sub> was written to Byte 8)
- Controller (host) will need to acknowledge each byte
- · Controller (host) will send a not acknowledge bit
- · Controller (host) will send a stop bit

	Index Block Read Operation						
Cor	ntroller (Host)		IDT (Slave/Receiver)				
Т	starT bit						
SI	ave Address						
WR	WRite						
			ACK				
Begi	nning Byte = N						
			ACK				
RT	Repeat starT						
SI	ave Address						
RD	ReaD						
			ACK				
			Data Byte Count=X				
	ACK						
			Beginning Byte N				
	ACK						
		<u>e</u>	0				
	0	X Byte	0				
	0	×	0				
	0						
			Byte N + X - 1				
N	Not acknowledge						
Р	stoP bit						

#### SMBus Table: Output Enable Register

Byte 0	Name	Control Function	Type	0	1	Default
Bit 7	Reserved					1
Bit 6	Reserved					1
Bit 5		Reserved				1
Bit 4	Reserved					1
Bit 3	DIF OE3	Output Enable	RW	Low/Low	Enabled	1
Bit 2	DIF OE3	Output Enable	RW	Low/Low	Enabled	1
Bit 1	DIF OE2	Output Enable	RW	Low/Low	Enabled	1
Bit 0	DIF OE1	Output Enable	RW	Low/Low	Enabled	1

#### SMBus Table: SS Readback and Vhigh Control Register

Byte 1	Name	Control Function	Туре	0	1	Default
Bit 7	SSENRB1	SS Enable Readback Bit1	R	00' for SS_EN_tri =	0, '01' for SS_EN_tri	Latch
Bit 6	SSENRB1	SS Enable Readback Bit0	R	= 'M', '11 for S	S_EN_tri = '1'	Latch
Bit 5	SSEN_SWCNTRL	Enable SW control of SS	RW	SS control locked	Values in B1[4:3] control SS amount.	0
Bit 4	SSENSW1	SS Enable Software Ctl Bit1	RW <sup>1</sup>	00' = SS Off, '0'	1' = -0.25% SS,	0
Bit 3	SSENSW0	SS Enable Software Ctl Bit0	RW <sup>1</sup>	'10' = Reserved	'11'= -0.5% SS	0
Bit 2		Reserved				1
Bit 1	AMPLITUDE 1	Controls Output Amplitude	RW	00 = 0.6V	01 = 0.7V	1
Bit 0	AMPLITUDE 0	Controls Catput Amplitude	RW	10= 0.8V	11 = 0.9V	0

<sup>1.</sup> B1[5] must be set to a 1 for these bits to have any effect on the part.

#### SMBus Table: DIF Slew Rate Control Register

Byte 2	Name	Control Function	Туре	0	1	Default
Bit 7	Reserved					
Bit 6	Reserved					1
Bit 5	Reserved					1
Bit 4	Reserved					1
Bit 3	SLEWRATESEL DIF3	Adjust Slew Rate of DIF3	RW	2.0V/ns	3.0V/ns	1
Bit 2	SLEWRATESEL DIF2	Adjust Slew Rate of DIF2	RW	2.0V/ns	3.0V/ns	1
Bit 1	SLEWRATESEL DIF1	Adjust Slew Rate of DIF3	RW	2.0V/ns	3.0V/ns	1
Bit 0	SLEWRATESEL DIF0	Adjust Slew Rate of DIF1	RW	2.0V/ns	3.0V/ns	1

#### SMBus Table: REF Control Register

Byte 3	Name	Control Function	Type	0	1	Default
Bit 7	REF	Slew Rate Control	RW	00 = Slowest	01 = Slow	0
Bit 6	IXLI	Siew Rate Control		10 = Fast	11 = Faster	1
Bit 5	REF Power Down Function	Wake-on-Lan Enable for REF	EF RW	REF does not run in	REF runs in Power	0
Dit 5		Wake on Earl Enable for KET	1200	Power Down	Down	Ū
Bit 4	REF OE	REF Output Enable	RW	Low	Enabled	1
Bit 3		Reserved				1
Bit 2		Reserved				1
Bit 1	Reserved					1
Bit 0	Reserved					1

Byte 4 is reserved and reads back 'hFF'.

#### SMBus Table: Revision and Vendor ID Register

Byte 5	Name	Control Function	Туре	0	1	Default
Bit 7	RID3		R			0
Bit 6	RID2	Revision ID	R	Λ rev -	0	
Bit 5	RID1		R	A rev = 0000		0
Bit 4	RID0		R		0	
Bit 3	VID3		R			0
Bit 2	VID2	VENDOR ID	R	0001	- IDT	0
Bit 1	VID1	VENDOR ID	R	0001 = IDT		0
Bit 0	VID0		R			1

#### SMBus Table: Device Type/Device ID

Byte 6	Name	Control Function	Туре	0	1	Default
Bit 7	Device Type1	Device Type	R	00 = FGV, 01 = DBV,		0
Bit 6	Device Type0	Device Type	R	10 = DMV, 11= Reserved		0
Bit 5	Device ID5		R			0
Bit 4	Device ID4		R			
Bit 3	Device ID3	Device ID	R	000100 bins	any or 04 hoy	0
Bit 2	Device ID2	Device ID	R	000100 billa	000100 binary or 04 hex	
Bit 1	Device ID1		R	1		0
Bit 0	Device ID0		R			0

#### SMBus Table: Byte Count Register

Byte 7	Name	Control Function	Type	0	1	Default
Bit 7	Reserved					
Bit 6	Reserved					0
Bit 5	Reserved					0
Bit 4	BC4		RW			0
Bit 3	BC3		RW	Writing to this regist	er will configure how	1
Bit 2	BC2	Byte Count Programming	RW	many bytes will be r	ead back, default is	0
Bit 1	BC1		RW	= 8 b	ytes.	0
Bit 0	BC0		RW			0

# **Recommended Crystal Characteristics (3225 package)**

PARAMETER	VALUE	UNITS	NOTES
Frequency	25	MHz	1
Resonance Mode	Fundamental	ı	1
Frequency Tolerance @ 25°C	±20	PPM Max	1
Frequency Stability, ref @ 25°C Over Operating Temperature Range	±20	PPM Max	1
Temperature Range (commercial)	0~70	°C	1
Temperature Range (industrial)	-40~85	°C	2
Equivalent Series Resistance (ESR)	50	Ω Max	1
Shunt Capacitance (C <sub>O</sub> )	7	pF Max	1
Load Capacitance (C <sub>L</sub> )	8	pF Max	1
Drive Level	0.3	mW Max	1
Aging per year	±5	PPM Max	1

#### Notes:

- 1. FOX 603-25-150.
- 2. For I-temp, FOX 603-25-261.

# **Thermal Characteristics**

PARAMETER	SYMBOL	CONDITIONS	PKG	TYP.	UNITS	NOTES
Thermal Resistance	$\theta_{JC}$	Junction to Case	NLG32	42	°C/W	1
	$\theta_{Jb}$	Junction to Base		2.4	°C/W	1
	$\theta_{JA0}$	Junction to Air, still air		39	°C/W	1
	$\theta_{JA1}$	Junction to Air, 1 m/s air flow	INLUGZ	33	°C/W	1
	$\theta_{JA3}$	Junction to Air, 3 m/s air flow		28	°C/W	1
	$\theta_{JA5}$	Junction to Air, 5 m/s air flow		27	°C/W	1

<sup>&</sup>lt;sup>1</sup>ePad soldered to board

# **Marking Diagrams**



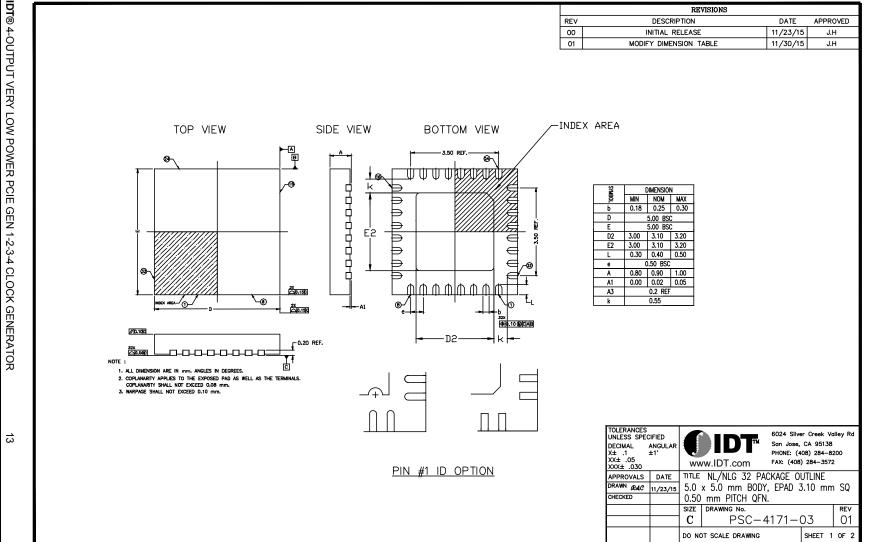


#### Notes:

- 1. Line 2 is the truncated part number.
- 2. 'L' denotes RoHS compliant package.
- 3. 'I' denotes industrial temperature grade.
- 4. 'YYWW' is the last two digits of the year and week that the part was assembled.
- 5. 'COO' denotes country of origin.
- 6. 'LOT' is the lot number.

Package Outline and Dimensions (NLG32)

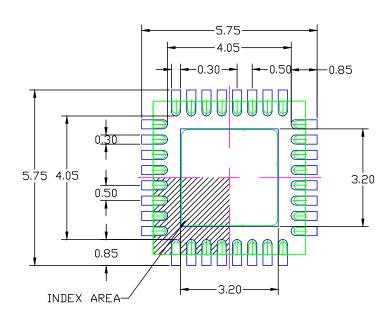
# JUNE 22, 2017



Package Outline and Dimensions (NLG32), cont.

DT® 4-OUTPUT VERY LOW POWER PCIE GEN 1-2-3-4 CLOCK GENERATOR

#### REVISIONS APPROVED REV DESCRIPTION DATE 00 INITIAL RELEASE 11/23/15 J.H 01 MODIFY DIMENSION TABLE 11/30/15 J.H



RECOMMENDED LAND PATTERN.

#### NOTES:

- 1. ALL DIMENSIONS ARE IN mm. ANGLES IN DEGREES.
  2. TOP DOWN VIEW. AS VIEWED ON PCB.
  3. COMPONENT OUTLINE SHOWS FOR REFERENCE IN GREEN.
  4. LAND PATTERN IN BLUE. NSMD PATTERN ASSUMED.
  5. LAND PATTERN RECOMMENDATION PER IPC—7351B GENERIC REQUIREMENT FOR SURFACE MOUNT DESIGN AND LAND PATTERN.

TOLERANCES UNLESS SPECIFIED DECIMAL ANGULAR X± .1 ±1* XX± .05 XXX± .030		6024 Silver Creek Valley Rd San Jose, CA 95138 PHONE: (408) 284–8200 FAX: (408) 284–3572			
APPROVALS	DATE	TITLE	NL/NLG 32 PACKAGE (	OUTLINE	
DRAWN PXP	12/20/06		x 5.0 mm BODY, EPAD	3.10 mm	n SQ
CHECKED		0.50	mm PITCH QFN.		
		SIZE	DRAWING No.		REV
		С	PSC-4171-	03	01
		DO NO	OT SCALE DRAWING	SHEET 2	OF 2

# **Ordering Information**

Part / Order Number	Shipping Packaging	Package	Temperature
9FGV0441AKLF	Trays	32-pin VFQFPN	0 to +70° C
9FGV0441AKLFT	Tape and Reel	32-pin VFQFPN	0 to +70° C
9FGV0441AKILF	Trays	32-pin VFQFPN	-40 to +85° C
9FGV0441AKILFT	Tape and Reel	32-pin VFQFPN	-40 to +85° C

<sup>&</sup>quot;LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

# **Revision History**

Rev.	Issue Date	Initiator	Description	Page #
Е	10/18/2016	RDW	Removed IDT crystal part number	
F	6/22/2017	RG	Updated front page Gendes to reflect the PCIe Gen4 updates. Updated Electrical Characteristics - Filtered Phase Jitter Parameters - PCIe Common Clocked (CC) Architectures and added PCIe Gen4 Data	1,7

<sup>&</sup>quot;A" is the device revision designator (will not correlate with the datasheet revision).

# Innovate with IDT and accelerate your future networks. Contact:

www.IDT.com

For Sales

800-345-7015 408-284-8200

www.idt.com/go/sales

For Tech Support

www.idt.com/go/support

#### **Corporate Headquarters**

Integrated Device Technology, Inc. www.idt.com

DISCLAIMER Integrated Device Technology, Inc. (IDT) and its affiliated companies (herein referred to as "IDT") reserve the right to modify the products and/or specifications described herein at any time, without notice, at IDT's sole discretion. Performance specifications and operating parameters of the described products are determined in an independent state and are not guaranteed to perform the same way when installed in customer products. The information contained herein is provided without representation or warranty of any kind, whether express or implied, including, but not limited to, the suitability of IDT's products for any particular purpose, an implied warranty of merchantability, or non-infringement of the intellectual property rights of others. This document is presented only as a guide and does not convey any license under intellectual property rights of IDT or any third parties.

IDT's products are not intended for use in applications involving extreme environmental conditions or in life support systems or similar devices where the failure or malfunction of an IDT product can be reasonably expected to significantly affect the health or safety of users. Anyone using an IDT product in such a manner does so at their own risk, absent an express, written agreement by IDT.

Integrated Device Technology, IDT and the IDT logo are trademarks or registered trademarks of IDT and its subsidiaries in the United States and other countries. Other trademarks used herein are the property of IDT or their respective third party owners. For datasheet type definitions and a glossary of common terms, visit <a href="https://www.idt.com/go/glossary">www.idt.com/go/glossary</a>. Integrated Device Technology, Inc.. All rights reserved.

